

		<b>APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL</b>			Page 1
Component Title: INTEGRATED CIRCUITS, SILICON MONOLITHIC, PULSE WIDTH MODULATOR		Executive Member: CNES		Date: 02/12/2024	Appl. No. 344D
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Components (including series and families) submitted for Extension of Qualification Approval:					
ESCC COMPONENT NO.	VARIANTS	RANGE OF COMPONENTS	BASED ON	TEST VEHICLE / S	COMPONENT SIMILAR
9108 020	01; 02	FP8	Type ST1843	9108 020 01F	All variant
9108 021	01; 02	FP8	Type ST1845	9108 021 01FR	All variant
Component Manufacturer ST Microelectronics		Location of Manufacturing Plant(s) Rennes 35041 – France		Date of original qualification approval: Date: 14/11/2016  Certificate Ref No. 344	
ESCC Specifications used for Maintenance of qualification testing: Generic: 9000 Issue: 12  Detail(s): 9108/020 Issue: 6 9108/021 Issue: 5		Deviations to LVT testing and Detail Specification used: No <input checked="" type="checkbox"/> Yes <input type="checkbox"/> (supply details in Box 15)  Deviation from current Specifications: No <input checked="" type="checkbox"/> Yes <input type="checkbox"/> (Supply details)		Qualification Extension Report reference and date: 33325F9201 DC 2326A ST1843FKG F4 SG2 33406FF001 DC 2410E ST1845RKG Full F4	
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Summary of procurement or equivalent test results during current validity period in support of this application (those to ESCC listed first)					
Project Name	Testing Level	LAT	Date code	Quantity Delivered	
See Ventes Jan 2023_Nov 2024.xls					
PID changes since start of qualification None <input checked="" type="checkbox"/> Minor* <input type="checkbox"/> Major* <input type="checkbox"/> *Provide details in box:		Current PID Verified by: <u>L. Baczowski, CNES</u> Name of Executive Representative Ref No: 8303834 (PWM) & 8097046 (generic) Issue: 6 & 39 Date: 02/012/2024 Rev Date: 27/11/2018 & 13/10/2024			
11					
Current Manufacturing facilities surveyed by: <u>CNES (JB Sauveplane)</u> on <u>12/07/2023</u> (Name of Executive Representative) (Date)					
Satisfactory: Yes <input checked="" type="checkbox"/> No <input type="checkbox"/> Explain					
Report Reference: <u>CR-Activités ST Juillet 2023</u>					



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Failure Analysis, DPA, NCCS available: Yes  No  (Supply data)

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Ref. No's and purposes:

The undersigned hereby certifies on behalf of the ESCC Executive - that the above information is correct; - that the appropriate documentation has been evaluated; - that full compliance to all ESCC requirements is evidence (except as stated in box 15); - that the reports and data are available at the ESCC Executive and therefore applies on behalf of CNES as the responsible Executive Member for ESCC qualification status to be extended to the component(s) listed herein.

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Date: 19/12/2024

L. Fontaine, CNES

(Signature of the Executive Coordinator)

Continuation of Boxes above:

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Non compliance to ESCC requirements:

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No.:	Specification	Paragraph	Non compliance

Additional tasks required to achieve full compliance for ESCC qualification or rationale for acceptability of noncompliance:

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Executive Manager Disposition

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Application Approval: Yes  No

Action / Remarks:

Date:

B. Schade: Head of the Quality Department



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**ANNEX 1: LIST OF TESTS DONE TO SUPPORT EXTENSION OF QUALIFICATION**

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Tests conducted in compliance with:

- ESCC 9000 generic specification; Chart F4 (for ESCC/QPL parts);
- Or PID-TFD (for ESCC/QML parts)

Tests vehicle identification/description:

ESCC 9108 020 01 ID 33325F9201 ST1843FKG F4 SG2 DC 2326A	ESCC 9108 021 01 33406FF001 ST1845RKG DC 2410E Full F4
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Detail Specification reference: 9108/020 ; 9108/021

Chart F4	Test	Tick when done	Conditions	Date Code Diffusion Lot	Tested Qty	No. of Rejects	Comments if not performed. Comments on Rejection
Environmental/Mechanical Subgroup	Mechanical Shock	<input checked="" type="checkbox"/>	MIL-STD-883, Test Method 2002	2410	15	0	
	Vibration	<input checked="" type="checkbox"/>	MIL-STD-883, Test Method 2007	2410	15	0	
	Constant Acceleration	<input checked="" type="checkbox"/>	MIL-STD-883, Test Method 2001	2410	15	0	
	Seal (Fine and Gross Leak)	<input checked="" type="checkbox"/>	MIL-STD-883, Test Method 1014	2410	15	0	
	Intermediate and End-Point Electrical Measurements	<input checked="" type="checkbox"/>	Intermediate and End-Point Electrical Measurements in the Detail Specification	2410	15	0	
	External Visual Inspection	<input checked="" type="checkbox"/>	ESCC Basic Specification No. 20500	2410	15	0	
	Thermal Shock	<input checked="" type="checkbox"/>	MIL-STD-883. Test Method 1011	2410	15	0	
	Temperature cycling	<input checked="" type="checkbox"/>	MIL-STD-883, Test Method 1010	2410	15	0	
	Moisture Resistance	<input checked="" type="checkbox"/>	MIL-STD-883, Test Method 1004	2410	15	0	
	Seal (Fine and Gross Leak)	<input checked="" type="checkbox"/>	MIL-STD-883, Test Method 1014	2410	15	0	
	Intermediate and End-Point Electrical Measurements	<input checked="" type="checkbox"/>	Intermediate and End-Point Electrical Measurements in the Detail Specification	2410	15	0	
	External Visual Inspection	<input checked="" type="checkbox"/>	ESCC Basic Specification No. 20500	2410	15	0	



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Chart F4	Test	Tick when done	Conditions	Date Code Diffusion Lot	Tested Qty	No. of Rejects	Comments if not performed. Comments on Rejection
Endurance Subgroup	Operating Life	<input checked="" type="checkbox"/>	MIL-STD-883, Test Method 1005	2326 2410	30	0	
	Intermediate and End-Point Electrical Measurements	<input checked="" type="checkbox"/>	Intermediate and End-Point Electrical Measurements in the Detail Specification	2326 2410	30	0	
	Seal (Fine and Gross Leak)	<input checked="" type="checkbox"/>	MIL-STD-883, Test Method 1014	2326 2410	30	0	
	External Visual Inspection	<input checked="" type="checkbox"/>	ESCC Basic Specification No. 20500	2326 2410	30	0	
Assembly Capability Subgroup	Permanence of Marking	<input type="checkbox"/>	ESCC Basic Specification No. 24800				Not applicable for laser marking
	Terminal Strength	<input checked="" type="checkbox"/>	MIL-STD-883, Test Method 2004	2410	5	0	
	Internal Visual Inspection	<input checked="" type="checkbox"/>	ESCC Basic Specification No. 20400	2410	5	0	
	Bond Strength	<input checked="" type="checkbox"/>	MIL-STD-883 Test Method 2011	2410	3	0	
	Die Shear or Substrate Attach Strength	<input checked="" type="checkbox"/>	MIL-STD-883 Test Method 2019 or 2027	2410	3	0	
Additional Tests	RGA	<input type="checkbox"/>	MIL-STD-883 Test Method 1018.7				Only applicable to single phase qualification of Wire-bonded Integrated Circuits



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NOTES ON THE COMPLETION OF THE APPLICATION FORM FOR ESCC QUALIFICATION EXTENSION APPROVAL

ENTRIES

- Form heading** shall indicate: - the title of the component as given in its detail specification or the name of the series, family; - the Executive Member; - the entering date; - the certificate number and its sequential suffix.
- Box 1** shall provide details given in the table; in particular there shall be listed: - the variants or range of variants; - the range of components (the ESCC code is recommended to indicate the values or values range, the tolerance, the voltage, etc); the designation given in the detail specification as 'base on'; - under Test Vehicle enter either an ESCC code or the specific characteristic capable of identifying the component tested (e.g., voltage of coil for a relay); - under component similar enter a cross if relevant.
- Box 2; 3 and 4** As per QPL entry; otherwise, an explanation of the changes must be supplied.
- Box 5** Will show the ESCC Generic and Detail specifications, including issue number and revision letter, current at the time the tests reported were performed. If the specifications are different from those current on the date of the application, see Box 6.
- Box 6** Will show the deviations from the Generic and Detail Specifications listed in Box 5, in particular deviations from testing. In case of deviations this must be listed in Box 15. In case the referenced specification in Box 5 have currently a different issue and/or revision indicate also whether the test data deviates or not from such current documents.
- Box 7** Must reference the report(s) supplied in support of the application.
- Box 8** Should provide the details of procurement to the full ESCC System, documentation of all of which should already have been delivered to the ESCC Executive under the terms of the relevant Generic Specification. An appropriate table has been drawn in this box.
- Box 9** If the PID evolved after the Original Qualification or after the last Extension of Qualification, adequate details of such evolution shall be provided together with the reasons for the changes. Major changes shall be clearly marked.
- Box 10** Identify the current PID issue status, date and actual date of verification. The date of verification of the current PID should be arranged as close as possible to the required date of extension.
- Box 11** This box can be completed only after a physical visit to the plant to confirm that no unexplained changes occurred and that the practices, procedures, material, etc. used in manufacturing the components are as described in the PID. This survey shall be carried out in accordance with the requirements of ESCC Basic Specification No. 20200 and its findings shall be recorded.
- Box 12** Provide details of, or reference to, any Destructive Physical Analysis (DPA) and Failure Analysis reports as well as any Nonconformance(s) (NCCS) occurred during the qualification validity period, stating if established corrective action have produced satisfactory results.
- Box 13** Enter only the name of the Executive Member (i.e., CNES, DLR, ESTEC, etc.) and the signature of the responsible Executive Coordinator.
- Box 14** To be used when there is a need to expand any of the boxes from 1 through 12. Identify box affected and reference the Box 14 in the relevant Box. Box 14 can be broken into 14a, 14b, etc. if several boxes have to be expanded.
- Box 15** Fill in Table as requested.
- Box 16** Any additional action deemed necessary by the Executive Member to bring the submitted data to a standard likely to be accepted by the ESCC Executive should be listed herein or the reason(s) to accept the noncompliance.
- Box 17** All Executive Manager recommendations on the application itself, special conditions or restrictions, modifications of the QPL or QML entry, letters to the manufacturer, etc. shall be entered clearly in Box 19, signed by the representative for ESA, and dated.
- Box 18** Fill in Table as requested.
- Box 19** Confidential Details of PID changes including those of a confidential nature, shall be provided.
- Box 20** State noncompliance with reference to specification(s) and paragraph(s). To simplify reference in Box 16 each nonconformance shall be sequentially numbered. If relevant state 'None'.
- Box 21** Any additional action deemed necessary by the Executive Member to bring the submitted data to a standard likely to be accepted by the ESCC Executive should be listed herein or the reason(s) to accept the noncompliance.
- Box 22** Additional Comments.